# EH2745ETTS-7.3728M



-7.3728M

Tri-State (High Impedance)

Pin 1 Connection

- Nominal Frequency

7.3728MHz

TS

Duty Cycle 50 ±10(%)

EH27 45 ET RoHS Compliant (Pb-free) 2.5V 4 Pad 5mm x 7mm Ceramic SMD LVCMOS Oscillator

Frequency Tolerance/Stability ±50ppm Maximum

Operating Temperature Range --40°C to +85°C

### **ELECTRICAL SPECIFICATIONS**

Series -

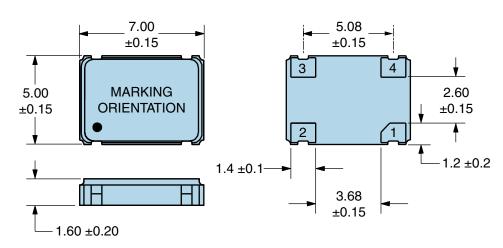
| Nominal Frequency                     | 7.3728MHz   |
|---------------------------------------|---|
| Frequency Tolerance/Stability         | ±50ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the<br>Operating Temperature Range, Supply Voltage Change, Output Load Change, First Year Aging at 25°,<br>260°C Reflow, Shock, and Vibration) |
| Aging at 25°C                         | ±5ppm/Year Maximum  |
| Operating Temperature Range           | -40°C to +85°C  |
| Supply Voltage                        | 2.5Vdc ±5%  |
| Input Current                         | 6mA Maximum (No Load)   |
| Output Voltage Logic High (Voh)       | 90% of Vdd Minimum (IOH = -8mA)   |
| Output Voltage Logic Low (Vol)        | 10% of Vdd Maximum (IOL = +8mA)   |
| Rise/Fall Time                        | 6nSec Maximum (Measured at 20% to 80% of waveform)  |
| Duty Cycle                            | 50 ±10(%) (Measured at 50% of waveform)   |
| Load Drive Capability                 | 15pF Maximum  |
| Output Logic Type                     | CMOS  |
| Pin 1 Connection                      | Tri-State (High Impedance)  |
| Tri-State Input Voltage (Vih and Vil) | 90% of Vdd Minimum or No Connect to Enable Output, 10% of Vdd Maximum to Disable Output (High Impedance)  |
| Standby Current                       | 10μA Maximum (Pin 1 = Ground)   |
| Absolute Clock Jitter                 | ±100pSec Maximum  |
| Start Up Time                         | 10mSec Maximum  |
| Storage Temperature Range             | -55°C to +125°C   |

### **ENVIRONMENTAL & MECHANICAL SPECIFICATIONS**

| ESD Susceptibility           | MIL-STD-883, Method 3015, Class 1, HBM: 1500V |
|------------------------------|---|
| Fine Leak Test               | MIL-STD-883, Method 1014, Condition A         |
| Flammability                 | UL94-V0                                       |
| Gross Leak Test              | MIL-STD-883, Method 1014, Condition C         |
| Mechanical Shock             | MIL-STD-883, Method 2002, Condition B         |
| Moisture Resistance          | MIL-STD-883, Method 1004                      |
| Moisture Sensitivity         | J-STD-020, MSL 1                              |
| Resistance to Soldering Heat | MIL-STD-202, Method 210, Condition K          |
| Resistance to Solvents       | MIL-STD-202, Method 215                       |
| Solderability                | MIL-STD-883, Method 2003                      |
| Temperature Cycling          | MIL-STD-883, Method 1010, Condition B         |
| Vibration                    | MIL-STD-883, Method 2007, Condition A         |

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## **MECHANICAL DIMENSIONS (all dimensions in millimeters)**

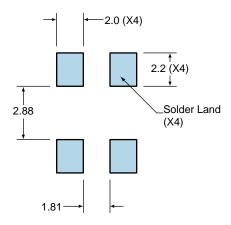


|  | EC<br>COR | <br>_ | <br>_ |
|--|-----------|-------|-------|
|  |           |       |       |

| PIN       | CONNECTION          |
|-----------|---------------------|
| 1         | Tri-State           |
| 2         | Case Ground         |
| 3         | Output              |
| 4         | Supply Voltage      |
|           |                     |
| LINE      | MARKING             |
| LINE      | MARKING             |
| LINE<br>1 | MARKING<br>ECLIPTEK |
|           |                     |

### Suggested Solder Pad Layout

All Dimensions in Millimeters



All Tolerances are ±0.1

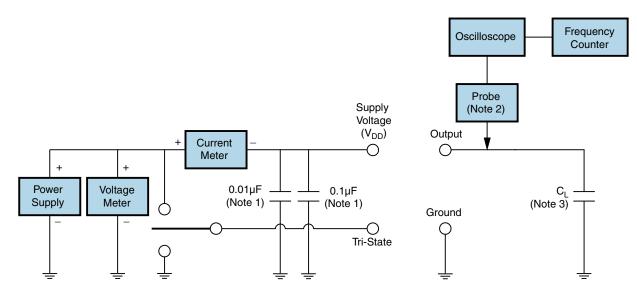
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#### **OUTPUT WAVEFORM & TIMING DIAGRAM**



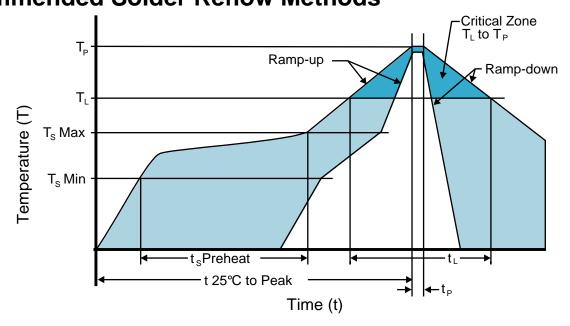
**Test Circuit for CMOS Output** 



- Note 1: An external 0.01µF ceramic bypass capacitor in parallel with a 0.1µF high frequency ceramic bypass capacitor close (less than 2mm) to the package ground and supply voltage pin is required.
- Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended. Note 3: Capacitance value C<sub>L</sub> includes sum of all probe and fixture capacitance.



# EH2745ETTS-7.3728M Recommended Solder Reflow Methods



## **High Temperature Infrared/Convection**

| <b>3</b> 1  |   |
|---|---|
| T <sub>s</sub> MAX to T <sub>L</sub> (Ramp-up Rate)         | 3°C/second Maximum                                |
| Preheat   |   |
| - Temperature Minimum (T <sub>s</sub> MIN)                  | 150°C   |
| <ul> <li>Temperature Typical (T<sub>s</sub> TYP)</li> </ul> | 175°C   |
| <ul> <li>Temperature Maximum (T<sub>s</sub> MAX)</li> </ul> | 200°C   |
| - Time (t <sub>s</sub> MIN)                                 | 60 - 180 Seconds                                  |
| Ramp-up Rate (T⊾ to T <sub>P</sub> )                        | 3°C/second Maximum                                |
| Time Maintained Above:                                      |   |
| - Temperature (T∟)  | 217°C   |
| - Time (t∟)   | 60 - 150 Seconds                                  |
| Peak Temperature (T <sub>P</sub> )                          | 260°C Maximum for 10 Seconds Maximum              |
| Target Peak Temperature (T <sub>P</sub> Target)             | 250°C +0/-5°C                                     |
| Time within 5°C of actual peak (t <sub>p</sub> )            | 20 - 40 seconds                                   |
| Ramp-down Rate  | 6°C/second Maximum                                |
| Time 25°C to Peak Temperature (t)                           | 8 minutes Maximum                                 |
| Moisture Sensitivity Level                                  | Level 1   |
| Additional Notes  | Temperatures shown are applied to body of device. |
|   |   |



## **Recommended Solder Reflow Methods**

EH2745ETTS-7.3728M



### Low Temperature Infrared/Convection 240°C

| T <sub>s</sub> MAX to T <sub>L</sub> (Ramp-up Rate)         | 5°C/second Maximum                                     |
|---|--|
| Preheat   |  |
| - Temperature Minimum (T <sub>s</sub> MIN)                  | N/A  |
| <ul> <li>Temperature Typical (T<sub>s</sub> TYP)</li> </ul> | 150°C  |
| <ul> <li>Temperature Maximum (T<sub>s</sub> MAX)</li> </ul> | N/A  |
| - Time (t <sub>s</sub> MIN)                                 | 60 - 120 Seconds                                       |
| Ramp-up Rate (T⊾ to T <sub>P</sub> )                        | 5°C/second Maximum                                     |
| Time Maintained Above:                                      |  |
| - Temperature (T∟)  | 150°C  |
| - Time (t∟)   | 200 Seconds Maximum                                    |
| Peak Temperature (T <sub>P</sub> )                          | 240°C Maximum  |
| Target Peak Temperature (T <sub>P</sub> Target)             | 240°C Maximum 1 Time / 230°C Maximum 2 Times           |
| Time within 5°C of actual peak (t <sub>P</sub> )            | 10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time |
| Ramp-down Rate  | 5°C/second Maximum                                     |
| Time 25°C to Peak Temperature (t)                           | N/A  |
| Moisture Sensitivity Level                                  | Level 1  |
| Additional Notes  | Temperatures shown are applied to body of device.      |
|   |  |

#### Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)

### **High Temperature Manual Soldering**

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures shown are applied to body of device.)